

# 2-Mbit (256K x 8) Static RAM

#### **Features**

- Pin and function compatible with CY7C1010CV33
- High speed
  □ t<sub>AA</sub> = 10 ns
- Low active power
  □ I<sub>CC</sub> = 90 mA at 10 ns
- Low CMOS standby power
  □ I<sub>SB2</sub> = 10 mA
- 2.0V data retention
- Automatic power down when deselected
- TTL-compatible inputs and outputs
- Easy memory expansion with CE and OE features
- Available in Pb-Free 36-pin SOJ and 44-pin TSOP II packages

## **Functional Description**

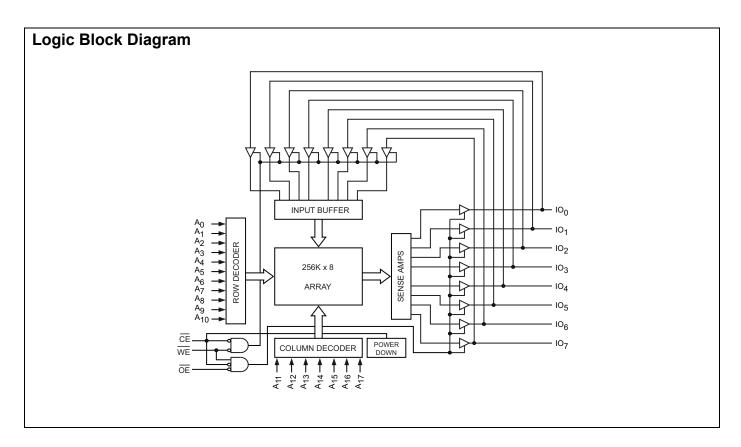
The CY7C1010DV33 is a high performance CMOS Static RAM organized as 256K words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable ( $\overline{\text{CE}}$ ), an active LOW Output Enable ( $\overline{\text{OE}}$ ), and three-state drivers. Writing to the device is accomplished by taking Chip Enable ( $\overline{\text{CE}}$ ) and Write Enable ( $\overline{\text{WE}}$ ) inputs LOW. Data on the eight I/O pins (I/O<sub>0</sub> through I/O<sub>7</sub>) is then written into the location specified on the address pins ( $A_0$  through  $A_{17}$ ).

Reading from the device is accomplished by taking Chip Enable ( $\overline{\text{CE}}$ ) and Output Enable ( $\overline{\text{OE}}$ ) LOW while forcing Write Enable (WE) HIGH. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.

The eight input and output pins (I/O $_0$  through I/O $_7$ ) are place<u>d in</u> a high impedance state when the device is deselected (CE HIGH), the <u>outputs</u> are disabled (OE HIGH), or during a Write operation (CE LOW, and WE LOW).

The CY7C1010DV33 is available in 36-pin SOJ and 44-pin TSOP II packages with center power and ground (revolutionary) pinout.

Refer to the Cypress application note AN1064, SRAM System Guidelines for best practice recommendations.





#### **Selection Guide**

| Description                  | -10 | Unit |
|------------------------------|-----|------|
| Maximum Access Time          | 10  | ns   |
| Maximum Operating Current    | 90  | mA   |
| Maximum CMOS Standby Current | 10  | mA   |

## **Pin Configuration**

Figure 1. 36-Pin SOJ [1]

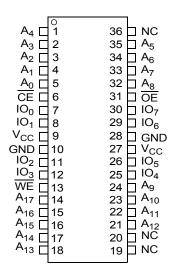
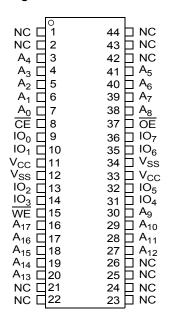


Figure 2. 44-Pin TSOP II [1]



#### Note:

<sup>1.</sup> NC pins are not connected on the die.



## **Maximum Ratings**

Exceeding the maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage Temperature ......-65°C to +150°C

Ambient Temperature with

Supply Voltage on  $V_{CC}$  Relative to GND  $^{[2]}....-0.5V$  to +4.6V

DC Voltage Applied to Outputs in High Z State  $^{[2]}$ ......-0.3V to  $V_{CC}$  + 0.3V

DC Input Voltage [2] ......-0.3V to V<sub>CC</sub> + 0.3V

| Current into Outputs (LOW) | . 20 mA |
|----------------------------|---------|
| Static Discharge Voltage   | >2001V  |
| (MIL-STD-883, Method 3015) |         |
| Latch Up Current>2         | 200 mA  |

## **Operating Range**

| Range      | Ambient<br>Temperature | V <sub>CC</sub> |
|------------|------------------------|-----------------|
| Industrial | –40°C to +85°C         | $3.3V\pm0.3V$   |

#### **Electrical Characteristics**

Over the Operating Range

|                  |   | Test Conditions  | Test Conditions      |            | -10                   |      |
|------------------|---|--|----------------------|------------|-----------------------|------|
| Parameter        | Description                                     |  |                      | Min        | Max                   | Unit |
| V <sub>OH</sub>  | Output HIGH Voltage                             | $V_{CC} = Min.; I_{OH} = -4.0 \text{ m/s}$   | 4                    | 2.4        |                       | V    |
| $V_{OL}$         | Output LOW Voltage                              | V <sub>CC</sub> = Min.; I <sub>OL</sub> = 8.0 mA   |                      |            | 0.4                   | V    |
| $V_{IH}$         | Input HIGH Voltage                              |  |                      | 2.0        | V <sub>CC</sub> + 0.3 | V    |
| V <sub>IL</sub>  | Input LOW Voltage <sup>[2]</sup>                |  |                      | -0.3       | 0.8                   | V    |
| I <sub>IX</sub>  | Input Leakage Current                           | $GND \le V_1 \le V_{CC}$   |                      | <b>–</b> 1 | +1                    | μΑ   |
| I <sub>OZ</sub>  | Output Leakage Current                          | $GND \le V_{OUT} \le V_{CC}$ , Outp  | ut Disabled          | <b>–</b> 1 | +1                    | μΑ   |
| I <sub>CC</sub>  | V <sub>CC</sub> Operating Supply Current        | V <sub>CC</sub> = Max.,  | 100 MHz              |            | 90                    | mA   |
|                  |   | $f = f_{MAX} = 1/t_{RC}$   | 83 MHz               |            | 80                    |      |
|                  |   |  | 66 MHz               |            | 70                    |      |
|                  |   |  | 40 MHz               |            | 60                    |      |
| I <sub>SB1</sub> | Automatic CE Power-down<br>Current —TTL Inputs  | Max. $V_{CC}$ , $\overline{CE} \ge V_{IH}$ ; $V_{IN} \ge V_{IN}$ , $f = f_{MAX}$                               | ≥ V <sub>IH</sub> or |            | 20                    | mA   |
| I <sub>SB2</sub> | Automatic CE Power-down<br>Current —CMOS Inputs | Max. $V_{CC}$ , $\overline{CE} \ge V_{CC} - 0.3$<br>$V_{IN} \ge V_{CC} - 0.3V$ , or $V_{IN} \le V_{CC} - 0.3V$ | 3V,<br>0.3V, f = 0   |            | 10                    | mA   |

#### Capacitance

Tested initially and after any design or process changes that may affect these parameters.

| Parameter        | Description       | Test Conditions                                    | SOJ | TSOP II | Unit |
|------------------|-------------------|--|-----|---------|------|
| C <sub>IN</sub>  | Input Capacitance | $T_A = 25^{\circ}C$ , $f = 1$ MHz, $V_{CC} = 3.3V$ | 8   | 8       | pF   |
| C <sub>OUT</sub> | IO Capacitance    |  | 8   | 8       | pF   |

#### **Thermal Resistance**

Tested initially and after any design or process changes that may affect these parameters.

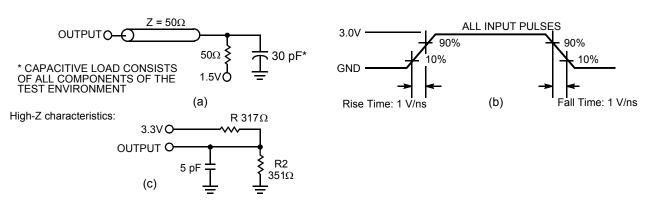
| Parameter       | Description                              | Test Conditions   | SOJ   | TSOP II | Unit |
|-----------------|--|---|-------|---------|------|
| $\Theta_{JA}$   | Thermal Resistance (Junction to Ambient) | Still air, soldered on a 3 × 4.5 inch, four layer printed circuit board | 59.17 | 50.66   | °C/W |
| Θ <sub>JC</sub> | Thermal Resistance (Junction to Case)    |   | 32.63 | 17.77   | °C/W |

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<sup>2.</sup>  $V_{IL}$  (min.) = -2.0V and  $V_{IH}$  (max.) =  $V_{CC}$  + 2.0V for pulse durations of less than 20 ns.



Figure 3. AC Test Loads and Waveforms  $^{[3]}$ 



#### Note

<sup>3.</sup> AC characteristics (except High-Z) are tested using the load conditions shown in Figure (a). High-Z characteristics are tested for all speeds using the test load shown in Figure (c).



## **AC Switching Characteristics**

Over the Operating Range [4]

|                                   |   | _1       | 10   |      |
|-----------------------------------|---|----------|------|------|
| Parameter                         | Description                                   | Min.     | Max. | Unit |
| Read Cycle                        | '   | <u>'</u> |      |      |
| t <sub>power</sub> <sup>[5]</sup> | V <sub>CC</sub> (typical) to the first access | 100      |      | μS   |
| t <sub>RC</sub>                   | Read Cycle Time                               | 10       |      | ns   |
| t <sub>AA</sub>                   | Address to Data Valid                         |          | 10   | ns   |
| t <sub>OHA</sub>                  | Data Hold from Address Change                 | 3        |      | ns   |
| t <sub>ACE</sub>                  | CE LOW to Data Valid                          |          | 10   | ns   |
| t <sub>DOE</sub>                  | OE LOW to Data Valid                          |          | 5    | ns   |
| t <sub>LZOE</sub>                 | OE LOW to Low-Z                               | 0        |      | ns   |
| t <sub>HZOE</sub>                 | OE HIGH to High-Z <sup>[6, 7]</sup>           |          | 5    | ns   |
| t <sub>LZCE</sub>                 | CE LOW to Low-Z <sup>[7]</sup>                | 3        |      | ns   |
| t <sub>HZCE</sub>                 | CE HIGH to High-Z <sup>[6, 7]</sup>           |          | 5    | ns   |
| t <sub>PU</sub>                   | CE LOW to Power-up                            | 0        |      | ns   |
| t <sub>PD</sub>                   | CE HIGH to Power-down                         |          | 10   | ns   |
| Write Cycle <sup>[8, 9]</sup>     | •   |          |      |      |
| t <sub>WC</sub>                   | Write Cycle Time                              | 10       |      | ns   |
| t <sub>SCE</sub>                  | CE LOW to Write End                           | 7        |      | ns   |
| t <sub>AW</sub>                   | Address Set-up to Write End                   | 7        |      | ns   |
| t <sub>HA</sub>                   | Address Hold from Write End                   | 0        |      | ns   |
| t <sub>SA</sub>                   | Address Set-up to Write Start                 | 0        |      | ns   |
| t <sub>PWE</sub>                  | WE Pulse Width                                | 7        |      | ns   |
| t <sub>SD</sub>                   | Data Set-up to Write End                      | 5        |      | ns   |
| t <sub>HD</sub>                   | Data Hold from Write End                      | 0        |      | ns   |
| t <sub>LZWE</sub>                 | WE HIGH to Low-Z <sup>[7]</sup>               | 3        |      | ns   |
| t <sub>HZWE</sub>                 | WE LOW to High-Z <sup>[6, 7]</sup>            |          | 5    | ns   |

- Notes:
  4. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V.
  5. t<sub>POWER</sub> gives the minimum amount of time that the power supply should be at stable, typical V<sub>CC</sub> values until the first memory access can be performed.
  6. t<sub>HZOE</sub>, t<sub>HZOE</sub>, and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in part (d) of AC Test Loads. Transition is measured when the outputs enter a high impedance state.
  7. At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZOE</sub>, t<sub>HZOE</sub> is less than t<sub>LZOE</sub>, and t<sub>HZWE</sub> for any given device.
  8. The internal Write time of the memory is defined by the overlap of CE LOW, and WE LOW. CE and WE must be LOW to initiate a Write, and the transition of either of these signals can terminate the Write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the Write.
  9. The minimum Write cycle time for Write Cycle No. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.

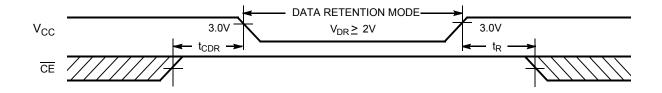


#### **Data Retention Characteristics**

Over the Operating Range [10]

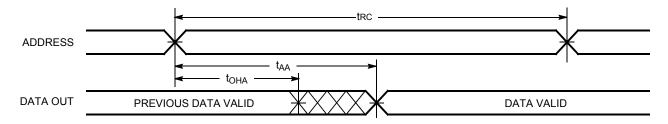
| Parameter             | Description                          | Conditions   | Min             | Max | Unit |
|-----------------------|--------------------------------------|--|-----------------|-----|------|
| $V_{DR}$              | V <sub>CC</sub> for Data Retention   |  | 2               |     | V    |
| I <sub>CCDR</sub>     | Data Retention Current               | $V_{CC} = V_{DR} = 2.0V, \overline{CE} \ge V_{CC} - 0.3V,$<br>$V_{IN} \ge V_{CC} - 0.3V \text{ or } V_{IN} \le 0.3V$ |                 | 10  | mA   |
| t <sub>CDR</sub> [11] | Chip Deselect to Data Retention Time |  | 0               |     | ns   |
| t <sub>R</sub> [12]   | Operation Recovery Time              |  | t <sub>RC</sub> |     | ns   |

## **Data Retention Waveform**



## **Switching Waveforms**

Figure 4. Read Cycle No. 1 [13, 14]



#### Notes

<sup>10.</sup> No inputs may exceed V<sub>CC</sub> + 0.3V

11. Tested initially and after any design or process changes that may affect these parameters.

12. Full device operation requires linear V<sub>CC</sub> ramp from V<sub>DR</sub> to V<sub>CC(min.)</sub> ≥ 50 μs or stable at V<sub>CC(min.)</sub> ≥ 50 μs.

13. The device is continuously selected. OE, CE = V<sub>IL</sub>.

14. WE is HIGH for read cycle.



## Switching Waveforms (continued)

Figure 5. Read Cycle No. 2 (OE Controlled) [14, 15]

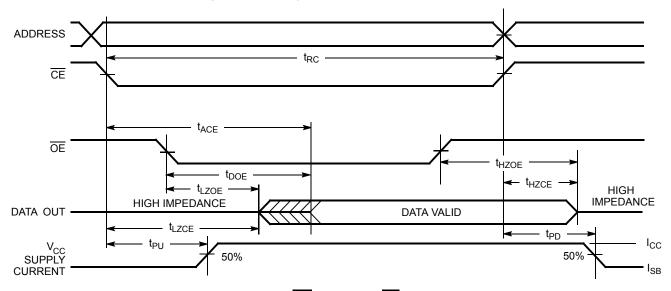
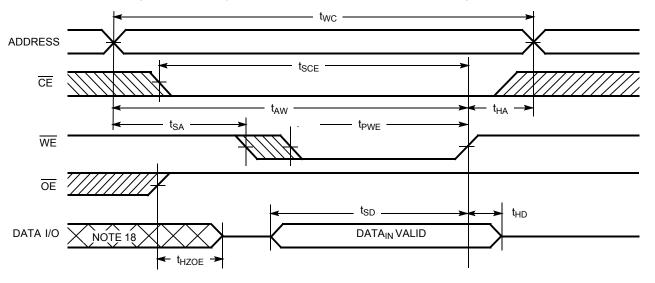


Figure 6. Write Cycle No. 1 (WE Controlled, OE HIGH During Write) [16, 17]



#### Notes

<sup>15.</sup> Address valid before or similar to CE transition LOW.

<sup>16.</sup> Data IO is high impedance if  $\overline{OE} = V_{IH}$ .

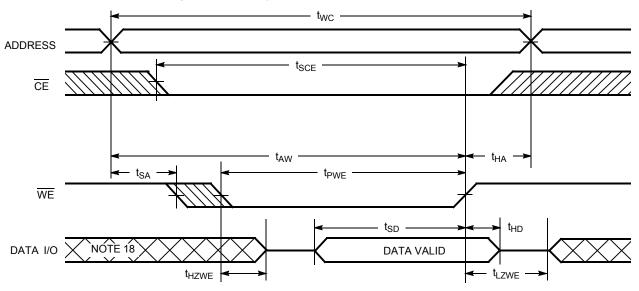
17. If  $\overline{CE}$  goes HIGH simultaneously with  $\overline{WE}$  going HIGH, the output remains in a high impedance state.

<sup>18.</sup> During this period, the I/Os are in output state and input signals should not be applied.



# Switching Waveforms (continued)

Figure 7. Write Cycle No. 2 ( $\overline{\text{WE}}$  Controlled,  $\overline{\text{OE}}$  LOW) [17]



## **Truth Table**

| CE | OE | WE | IO <sub>0</sub> -IO <sub>7</sub> | IO <sub>8</sub> -IO <sub>15</sub> | Mode                       | Power                      |
|----|----|----|----------------------------------|-----------------------------------|----------------------------|----------------------------|
| Н  | Х  | Х  | High-Z                           | High-Z                            | Power Down                 | Standby (I <sub>SB</sub> ) |
| L  | L  | Н  | Data Out                         | Data Out                          | Read All Bits              | Active (I <sub>CC</sub> )  |
| L  | Х  | L  | Data In                          | Data In                           | Write All Bits             | Active (I <sub>CC</sub> )  |
| L  | Н  | Н  | High-Z                           | High-Z                            | Selected, Outputs Disabled | Active (I <sub>CC</sub> )  |

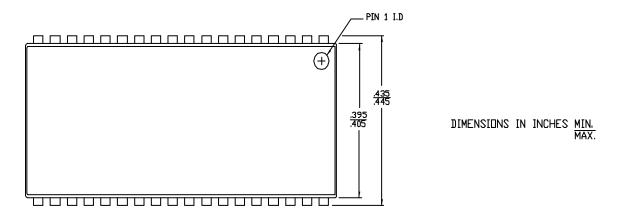
# **Ordering Information**

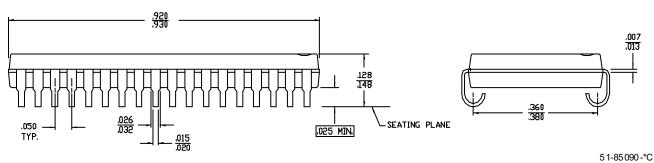
| Speed (ns) | Ordering Code       | Package<br>Diagram | Package Type                          | Operating Range |
|------------|---------------------|--------------------|---------------------------------------|-----------------|
| 10         | CY7C1010DV33-10VXI  | 51-85090           | 36-pin (400-Mil) Molded SOJ (Pb-free) | Industrial      |
|            | CY7C1010DV33-10ZSXI | 51-85087           | 44-pin TSOP II (Pb-Free)              |                 |



# **Package Diagrams**

Figure 8. 36-Pin (400-Mil) Molded SOJ (51-85090)



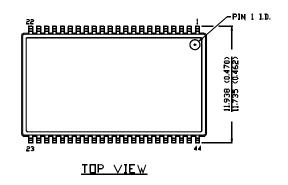


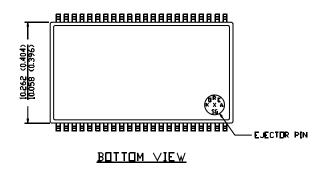


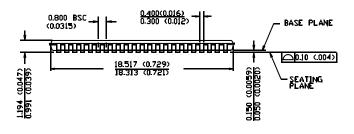
## Package Diagrams (continued)

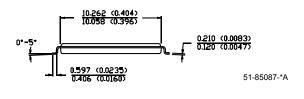
Figure 9. 44-Pin TSOP II (51-85087)

D[MENS|DN [N MM ([NCH) MAX MIN.











### **Document History Page**

| Document Title: CY7C1010DV33, 2-Mbit (256K x 8) Static RAM Document Number: 001-00062 |         |                    |                    |  |  |  |  |
|---|---------|--------------------|--------------------|--|--|--|--|
| REV.  | ECN NO. | Submission<br>Date | Orig. of<br>Change | Description of Change  |  |  |  |
| **  | 342195  | See ECN            | PCI                | New Data sheet   |  |  |  |
| *A  | 459073  | See ECN            | NXR                | Converted Preliminary to Final. Removed Commercial Operating Range from product offering. Removed -8 ns and -12 speed bin Removed the Pin definitions table. Modified Maximum Ratings for DC input voltage from -0.5V to -0.3V and $V_{CC}$ + 0.5V to $V_{CC}$ + 0.3V Changed $I_{CC}$ max from 65 mA to 90 mA Changed the description of $I_{IX}$ from "Input Load Current" to "Input Leakage Current" Updated the Thermal Resistance table. Updated footnote #7 on High-Z parameter measurement Added footnote #12 Updated the Ordering Information and replaced Package Name column with Package Diagram in the Ordering Information table. |  |  |  |
| *B  | 2602853 | 11/07/08           | VKN/PYRS           | Added 36-pin SOJ package and its related information   |  |  |  |

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